

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	18890	324/754,755,757,758,761,765.ccls. or 439/482.ccls. or 174/260,261,267,255.ccls. or 361/748,760,767,768,771,777,779.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 19:08
L2	1195	1 and @pd>"20041202"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 19:29
L3	3	((("5585282") or ("6686758") or ("5172050")).PN.	USPAT	OR	OFF	2005/09/21 19:29
S1	4615651	Silicon or Si or germanium or Ge or GaAs or Gallium Arsenide or Tin or Sn or GaP or Gallium Phosphide or GaSb or InAs or Indium Arsenide or InP or Indium Phosphide or InSb	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:28
S2	27225	S1 and penetrat\$3 and pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:27
S3	5360	S2 and (sharp or knife)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:15
S4	3021	S3 and (probe or pin or wedge)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:16
S5	1493	S4 and (interconnect or interposer or connector or socket or flip-chip or flat adj (pac or pack))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:18
S6	521	S5 and (protrude or protrusion or protrudes)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:19

S7	354	S6 not (tin or SN)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 18:27
S8	4328714	Silicon or Si or germanium or Ge or GaAs or Gallium Arsenide or GaP or Gallium Phosphide or GaSb or InAs or Indium Arsenide or InP or Indium Phosphide or InSb	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:32
S9	94606	S8 and pad and (integrated adj circuit or chip or wafer or die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:30
S10	13547	S9 and (sharp or knife or wedge)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 18:32
S11	547	S10 and (knife or wedge) with (Silicon or Si or germanium or Ge or GaAs or Gallium Arsenide or GaP or Gallium Phosphide or GaSb or InAs or Indium Arsenide or InP or Indium Phosphide or InSb)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/09/20 19:00
S12	2322	probe with (comprising or comprised or comprises or made) with (Silicon or Si or germanium or Ge or GaAs or Gallium Arsenide or GaP or Gallium Phosphide or GaSb or InAs or Indium Arsenide or InP or Indium Phosphide or InSb)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:14
S13	698	nakano and semiconductor and pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:17
S14	4816	semiconductor with probe and pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:17

S15	151	S14 and wedge	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:19
S16	103	chip adj carrier and wedge adj shap\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:21
S17	244	(die or chip) near3 carrier and wedge adj shap\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:22
S18	141	S17 not S16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/20 19:26
S19	1	("5580827").PN.	USPAT	OR	OFF	2005/09/20 19:30
S20	6	microminiature with tip with silicon	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 19:03
S21	8	((("2817002") or ("3921022") or ("3970887") or ("4141405") or ("4307507") or ("4685996") or ("4721885") or ("4916002"))).PN.	USPAT	OR	OFF	2005/09/20 20:15
S22	29699	micron.asn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 12:36
S23	6	S22 and (apex and knife-edge and semiconductor adj material and single).clm.	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 12:42
S25	1	("5523697").PN.	USPAT	OR	OFF	2005/09/21 13:57
S26	1	("6414506").PN.	USPAT	OR	OFF	2005/09/21 13:59
S27	1	("6127195").PN.	USPAT	OR	OFF	2005/09/21 14:01
S28	1	("6380754").PN.	USPAT	OR	OFF	2005/09/21 14:03

S29	1	("6657450").PN.	USPAT	OR	OFF	2005/09/21 14:05
S30	1	("6614249").PN.	USPAT	OR	OFF	2005/09/21 14:06
S31	1	("6686758").PN.	USPAT	OR	OFF	2005/09/21 14:12
S32	1	("6462571").PN.	USPAT	OR	OFF	2005/09/21 14:14
S33	1	("5326428").PN.	USPAT	OR	OFF	2005/09/21 14:22
S34	1	("5478779").PN.	USPAT	OR	OFF	2005/09/21 14:24
S35	8451	probe and (semiconductor or semiconductive) near3 material	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 14:25
S36	47	S35 and knife-edge	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 14:27
S37	282	S35 and apex	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 14:27
S38	257	S37 not S36	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/21 14:27